

**Notice of References Cited**

Application/Control No.

09/910,632

Applicant(s)/Patent Under  
Reexamination  
NEE ET AL.

Examiner

Huy Q Phan

Art Unit

2685

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,594,245 B1	07-2003	Rimhagen et al.	370/337
	B	US-6,385,454 B1	05-2002	Bahl et al.	455/450
	C	US-2002/0142777 A1	10-2002	McGovern et al.	455/450
	D	US-6,529,734 B1	03-2003	Lagneborg et al.	455/452.2
	E	US-6,125,278 A	09-2000	Wieczorek et al.	455/437
	F	US-6,188,905 B1	02-2001	Rudrapatna et al.	455/452.2
	G	US-2003/0125030 A1	07-2003	DIXON, ROBERT C.	455/447
	H	US-6,721,568 B1	04-2004	Gustavsson et al.	455/450
	I	US-6,084,866 A	07-2000	Dorenbosch et al.	370/331
	J	US-6,418,148 B1	07-2002	Kumar et al.	370/468
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.